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TECHNOLOGY CENTER 2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Vandervorst, et al.

App. No. : 10/091,226

Filed : February 28, 2002

For : METHOD AND APPARATUS  
FOR PERFORMING ATOMIC  
FORCE MICROSCOPY  
MEASUREMENTS

Examiner : Unknown

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John M. Carson, Reg. No. 34,503

PRELIMINARY AMENDMENT

United States Patent and Trademark Office  
P.O. Box 2327  
Arlington, VA 22202

Dear Sir:

Prior to examination of the above-identified application, please amend the application as follows:

IN THE SPECIFICATION:

Please insert the following paragraph between the title of the invention and background of the invention:

Related Applications

This application claims priority under 35 U.S.C. § 119(e) from U.S. Provisional Application No. 60/272,249, filed February 28, 2001, which is hereby incorporated by reference.